

## Publikationen

(2011): Conductivity and Charge Trapping After Electrical Stress in Amorphous and Polycrystalline Al<sub>2</sub>O<sub>3</sub>-Based Devices Studied With AFM-Related Techniques. In: IEEE Transactions on Nanotechnology, vol. 10, no. 2, pp. 344-351.

(2009): Crystallization and silicon diffusion nanoscale effects on the electrical properties of Al<sub>2</sub>O<sub>3</sub> based devices. In: Microelectronic Engineering, vol. 86, no. 7-9, pp. 1921-1924.